Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/830,049	OHNISHI ET AL.	
Examiner	Art Unit	
Linh V. Nguyen	2819	

	SEAR	CHED	
Class	Subclass	Date	Examiner
330	286,295 277	4/5/2006	LN
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INTERFERENCE SEARCHED						
Class	Subclass	Date	Examiner			
	<u> </u>					

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See East searched printout	4/5/2006	LN		